

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	50	("5698876" "5475646" "5808947" "4320881" "5818772" "5861660" "5883008" "5991212" "6005628" "4597080" "4841485" "4893072" "4918594" "5331164" "5473551" "5477492" "5495268" "5525912" "5606568" "5636163" "5724289" "5737342" "5742785" "5826007" "5930187" "6006350" "6065142" "6112067" "6208570" "6233701" "6243576" "3579199" "4166029" "4257261" "4261040" "4266292" "4287594" "4293950" "4306303" "4312067" "4323972" "4330838" "4334307" "4360911" "4369511" "4370641" "4387587" "4398284" "4422098" "4429368").pn.	USPAT	OR	ON	2006/03/29 13:24
S2	16	S1 and (redundant repair replace) and (test testing tester tested)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:13
S3	164569	(compare compared comparing comparison) and (redundant repair replace) and (test testing tester tested)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:14
S4	105247	(compare compared comparing comparison) and (redundant repair replace) and (test testing tester tested) and (fail error erroneous failure failing failed bad)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:15
S5	18449	(compare compared comparing comparison) and (redundant repair replace) and (test testing tester tested) and (fail error erroneous failure failing failed bad) and row and column	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:16
S6	4605	(compare compared comparing comparison) and (redundant repair replace) and (test testing tester tested) and (fail error erroneous failure failing failed bad) and row and column and (test with generat\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:18

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S7	3	S1 and S6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:18
S8	5	"6421286"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:48
S9	2	"20040205427"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:48

PALM INTRANET

Day : Monday
Date: 4/3/2006
Time: 08:43:09

Inventor Name Search Result

Your Search was:

Last Name = ICHIKAWA

First Name = OSAMU

Application#	Patent#	Status	Date Filed	Title	Inventor Name
06146790	4322735	150	05/05/1980	DISPLAY DEVICE	ICHIKAWA, OSAMU
06270030	4445132	150	06/03/1981	LED MODULE FOR A FLAT PANEL DISPLAY UNIT	ICHIKAWA, OSAMU
06414897	4432131	150	09/03/1982	METHOD FOR MANUFACTURING DISPLAY DEVICE	ICHIKAWA, OSAMU
06421099	4465543	150	09/22/1982	APPARATUS AND METHOD FOR ARRANGING SEMICONDUCTOR PELLETS	ICHIKAWA, OSAMU
06462771	Not Issued	166	02/01/1983	DISPLAY DEVICE	ICHIKAWA, OSAMU
06617351	4620094	150	06/05/1984	PHOTOELECTRIC ENCODER	ICHIKAWA, OSAMU
06640093	4729627	150	08/13/1984	OPTICAL FIBER CABLE FOR DETECTING LOW TEMPERATURE	ICHIKAWA, OSAMU
06714858	4701015	150	03/22/1985	WATERPROOF OPTICAL FIBER CABLE AND METHOD OF THE PRODUCTION THEREOF	ICHIKAWA, OSAMU
06778085	Not Issued	166	09/20/1985	ACTIVE MATRIX DISPLAY DEVICE	ICHIKAWA, OSAMU
06808376	4647927	150	12/16/1985	DISPLAY DEVICE	ICHIKAWA, OSAMU
07036454	4752113	150	04/09/1987	WATERPROOF OPTICAL FIBER CABLE	ICHIKAWA, OSAMU
07127554	Not Issued	166	12/02/1987	ACTIVE MATRIX DISPLAY DEVICE	ICHIKAWA, OSAMU
07332424	Not Issued	166	03/31/1989	ACTIVE MATRIX DISPLAY DEVICE	ICHIKAWA, OSAMU
07607750	5028916	150	10/31/1990	ACTIVE MATRIX DISPLAY DEVICE	ICHIKAWA, OSAMU
08726790	5783221	150	10/07/1996	CONTROL SYSTEM FOR AN INJECTION MOLDING MACHINE	ICHIKAWA, OSAMU
08868891	6143705	150	06/04/1997	CLEANING AGENT	ICHIKAWA, OSAMU
08899375	5948082	250	07/23/1997	COMPUTER SYSTEM HAVING A	ICHIKAWA, OSAMU

				DATA BUFFERING SYSTEM WHICH INCLUDES A MAIN RING BUFFER COMPRISED OF A PLURALITY OF SUB-RING BUFFERS CONNECTED IN A RING	
<u>09560126</u>	<u>6271677</u>	150	04/28/2000	Semiconductor integrated circuit and method for testing the semiconductor integrated circuit	ICHIKAWA, OSAMU
<u>09561342</u>	<u>6615389</u>	150	04/28/2000	DATABASE FOR DESIGNING INTEGRATED CIRCUIT DEVICE, AND METHOD FOR DESIGNING INTEGRATED CIRCUIT DEVICE	ICHIKAWA, OSAMU
<u>09658926</u>	<u>6514921</u>	150	09/11/2000	CLEANING AGENT	ICHIKAWA, OSAMU
<u>09789736</u>	<u>6410494</u>	150	02/22/2001	CLEANING AGENT	ICHIKAWA, OSAMU
<u>09971807</u>	Not Issued	93	10/05/2001	METHOD FOR HARD-COPYING WEB PAGES, METHOD FOR PRINTING DISPLAY SCREENS, SYSTEM FOR HARD-COPYING WEB PAGES, AND INTERNET CONNECTION DEVICE EQUIPPED WITH CURRENT-POSITION DETECTION CAPABILITIES	ICHIKAWA, OSAMU
<u>10187269</u>	<u>6734549</u>	150	07/02/2002	SEMICONDUCTOR WIRING SUBSTRATE, SEMICONDUCTOR DEVICE, METHOD FOR TESTING SEMICONDUCTOR DEVICE, AND METHOD FOR MOUNTING SEMICONDUCTOR DEVICE	ICHIKAWA, OSAMU
<u>10187413</u>	Not Issued	41	07/02/2002	Semiconductor integrated circuit and testing method for the same	ICHIKAWA, OSAMU
<u>10386726</u>	Not Issued	30	03/12/2003	Voice recognition apparatus, voice recognition apparatus and program thereof	ICHIKAWA, OSAMU
<u>10394068</u>	<u>6914274</u>	150	03/24/2003	THIN-FILM SEMICONDUCTOR EPITAXIAL SUBSTRATE HAVING BORON CONTAINING INTERFACE LAYER BETWEEN A COLLECTOR LAYER AND A SUB-COLLECTOR LAYER	ICHIKAWA, OSAMU
<u>10601660</u>	<u>6979091</u>	150	06/24/2003	DOOR MIRROR SET PLATE	ICHIKAWA, OSAMU
<u>10647506</u>	<u>6917215</u>	150	08/26/2003	SEMICONDUCTOR INTEGRATED CIRCUIT AND MEMORY TEST METHOD	ICHIKAWA, OSAMU
<u>10701607</u>	<u>6999823</u>	150	11/06/2003	POWER SHUT-OFF METHOD FOR INJECTION MOLDING MACHINE	ICHIKAWA, OSAMU
<u>10801440</u>	Not	71	03/16/2004	Sound source localization system, and	ICHIKAWA, OSAMU

	Issued			sound reflecting element	
<u>10804138</u>	Not Issued	30	03/19/2004	Semiconductor integrated circuit and test method thereof	ICHIKAWA, OSAMU
<u>10828230</u>	<u>7032196</u>	150	04/21/2004	SEMICONDUCTOR WIRING SUBSTRATE, SEMICONDUCTOR DEVICE, METHOD FOR TESTING SEMICONDUCTOR DEVICE, AND METHOD FOR MOUNTING SEMICONDUCTOR DEVICE	ICHIKAWA, OSAMU
<u>10828263</u>	Not Issued	30	04/21/2004	Semiconductor wiring substrate, semiconductor device, method for testing semiconductor device, and method for mounting semiconductor device	ICHIKAWA, OSAMU
<u>10828492</u>	Not Issued	61	04/21/2004	Semiconductor wiring substrate, semiconductor device, method for testing semiconductor device, and method for mounting semiconductor device	ICHIKAWA, OSAMU
<u>11024463</u>	Not Issued	30	12/30/2004	Test method for a semiconductor integrated circuit having a multi-cycle path and a semiconductor integrated circuit	ICHIKAWA, OSAMU
<u>11038493</u>	Not Issued	20	01/21/2005	Method for testing semiconductor integrated circuit	ICHIKAWA, OSAMU
<u>11075519</u>	Not Issued	25	03/09/2005	Signal noise reduction	ICHIKAWA, OSAMU
<u>11136831</u>	Not Issued	20	05/25/2005	Voice recording system, recording device, voice analysis device, voice recording method and program	ICHIKAWA, OSAMU
<u>11142323</u>	Not Issued	30	06/02/2005	Semiconductor integrated circuit and memory test method	ICHIKAWA, OSAMU
<u>11166345</u>	Not Issued	25	06/27/2005	Semiconductor integrated circuit and memory test method	ICHIKAWA, OSAMU
<u>11251172</u>	Not Issued	30	10/14/2005	Gas-liquid separator for a fuel cell system onboard a vehicle	ICHIKAWA, OSAMU
<u>11262010</u>	Not Issued	30	10/28/2005	Fuel cell system	ICHIKAWA, OSAMU
<u>11292047</u>	Not Issued	19	11/30/2005	Solenoid-operated cutoff valve for use with fuel cells	ICHIKAWA, OSAMU
<u>11298318</u>	Not Issued	20	12/08/2005	Noise reduction device, program and method	ICHIKAWA, OSAMU

Inventor Search Completed: No Records to Display.

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